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Microwave intermodulation distortion of MgB_2 thin films

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Abstract

The two tone intermodulation arising in MgB_2 thin films deposited in-situ by planar magnetron sputtering on sapphire substrates is studied. Samples are characterised using an open-ended dielectric puck resonator operating at 8.8 GHz. The experimental results show that the third order products increase with the two-tone input power with a slope ranging between 1.5 and 2.3. The behaviour can be understood introducing a mechanism of vortex penetration in grain boundaries as the most plausible source of non linearities in these films. This assumption is confirmed by the analysis of the field dependence of the surface resistance, that show a linear behaviour at all temperatures under test.

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The recent discovery of superconductivity in MgB_2 [1] has raised a worldwide interest in the scientific community because of its promising perspectives. In particular, applications of superconducting electronics where the use of closed cycle refrigerators is mandatory (such as hybrid receivers for telecommunications) could strongly benefit from this medium T_c superconductor. In this respect, the study of harmonic generation and intermodulation distortion (IMD) is a fundamental characterization tool for both the performance of passive devices in the microwave region and the understanding of the non linear microwave properties of magnesium diboride. Classically, we expect that a third order product signal arising in a non-linear responsive material should vary as the third power of the input signal. In superconducting materials, this has been observed in low temperature superconductors like niobium and niobium nitride.[2, 3] High temperature superconductors (HTS) follow the expected behaviour but at very low power levels only,[4, 5] whereas at higher power they usually show a quadratic dependence of IMD on the input signal.[4, 5, 6, 7, 8, 9] This has been generally ascribed to vortex penetration in weak links.[6, 7, 8]

In this letter, we present a detailed characterization of the microwave nonlinearity in MgB_2 performed by single tone and two tone measurements. In particular, we show that the IMD products have the same unusual behaviour found in HTS materials. These experimental results can be explained in the framework of a granular model of Josephson coupled grains.

We studied three MgB_2 thin films with inductively measured critical temperatures ranging between 20 and 31 K. These films have been realized using a fully in situ two step approach, by a planar magnetron sputtering technique in a UHV environment. Briefly, an amorphous Mg-B precursor is grown at room temperature on r-cut single crystal 10x10 mm^2 sapphire. After deposition, using a simple in situ manipulator, the sample is placed in a niobium box containing small amounts of Mg and then heated up to 800 ^oC. The box is closed using an indium gasket that guarantees hermetic sealing. The process is conducted in saturated Mg-vapor as in a ex-situ process, however it gives a surface film quality and reproducibility that are typical of an in situ process. Further details are reported elsewhere.[10] The film thickness, measured by Focused Ion Beam (FIB), is 0.5 μm $\pm$ 10%. X-ray diffraction $\theta - 2\theta$ measurements indicate a wide c-axis orientation of the surface.[10] Film morphology is investigated by Atomic Force Microscopy (AFM) and Scanning Electron Microscopy (SEM) analyses. AFM shows granular features at the surface, with average roughness of about 20 nm. SEM images with microprobe analysis show high composition uniformity over the full

substrate area. The films are labelled from #1 to #3 with increasing critical temperature. The main superconducting properties of all the samples under test are summarized in table I.

To investigate the power dependence of the microwave properties of this new superconductor, we performed in the same system configuration the measurement of the two tone intermodulation products and of the surface impedance Z_S=R_S+jX_S as a function of the input power. We used an open-ended dielectric single-crystal sapphire puck resonator (with a TE_{011} mode resonant frequency of 8.8 GHz) in close proximity to the film with a variable puck-to-sample distance. The experimental configuration was experimentally chosen observing at room temperature the distance that produces the largest perturbation in the cavity resonance. This procedure made us confident that each film has been positioned where the magnetic field is close to its maximum value. The enclosure of the resonator is made of OFHC copper and cooled by a standard two stage Gifford-McMahon cryocooler system from T_C down to 12K. For the measurement of IMD products, two pure frequencies f_1 and f_2 ($>f_1$) with equal amplitudes were generated by two phase-locked synthesizers. The two signals were combined and applied to the resonant cavity. The frequencies were separated symmetrically about the center frequency of the resonant cavity by an amount (δf) such that both frequencies were well within the 3-dB bandwidth of the resonator. All the IMD data presented in this paper are taken with δf=10 kHz while the resonance bandwidth was generally not less than 170 kHz. The output signals of the resonator (the two main tones f_1 and f_2 and the two third order IMD's at $2f_1$-f_2 and $2f_2$-f_1) were measured as a function of the input power by using a spectrum analyzer. Note that the measurement system does not involve an amplifier since the non-linearity inherent in a high gain active device would be too high to allow sensitive measurement of the intermodulation generated in the superconducting film. Further details are given elsewhere.[11, 12, 13]

All the samples under test showed a similar behaviour as a function of power, therefore for the sake of clarity we will show the experimental results obtained on sample #3 only. In Fig. 1 the output power at the main tones and the IMD third order products as a function of the circulating power P_{circ} are presented at different temperatures. In the inset P_{out} vs P_{circ} for the samples #1 and #2 at t=0.57 and 0.62 respectively is shown for comparison.

The power circulating in the cavity is evaluated using the following expression:[14]

$$P_{circ} = 10Log\left(\frac{2Q_L}{10^{-\frac{IL}{20}}}\right) + P_{out} \tag{1}$$

where Q_L is the loaded quality factor of the cavity, IL represents the insertion losses and P_{out} is the output power of the main tone. P_{circ} and P_{out} are expressed in dBm. There are two main reasons to plot the IMD products as a function of the circulating power instead of the more conventional input power: *i)* the behavior does not depend either on the input coupling or on the resonator quality factor, thus making the comparison amongst different devices simpler; *ii)* P_{circ} is directly proportional to the square of the mean amplitude of the microwave applied field $H_{r.f.}$, that is the relevant quantity for the study of the intrinsic properties in superconducting samples. $H_{r.f.}$ is expressed by the following relation:[14, 15]

$$H_{r.f.} = \sqrt{\frac{P_{circ}}{2\Gamma A}}, \tag{2}$$

where P_{circ} is expressed in Watt, A is the sample surface and Γ the geometrical factor of the cavity, experimentally determinated by using as a reference a superconducting YBCO sample of known surface resistance. In the case of the samples under test, Γ was equal to 403, 494 and 626 Ω for #1, #2 and #3 respectively with an error of 15%. The large difference in the geometrical factors are due to the different choices of the puck-sample distance.

In Fig. 1 we observe two important features: *i)* the power law dependence of the IMD products is constant with the circulating power and shows an exponent ranging between 1.5 and 1.8; *ii)* the output power of the IMD products decreases with the increasing temperature. In figure 2 the IMD slopes as a function of the reduced temperature are displayed for the samples under study. All values are almost temperature independent with an exponent ranging between 1.5 and 2.3. The error on the IMD slopes is estimated between 4 and 8 %.

In the single tone experiment, the quality factor Q and the resonant frequency f_0 of the dielectric resonator are measured as a function of the applied microwave field $H_{r.f.}$ as calculated using eq. 2. We estimate the changes in the surface resistance and in the surface reactance by using the simple general relation:[14]

$$R_S + j\Delta X_S = \Gamma\left[\left(\frac{1}{Q_0} - \frac{1}{Q_0^{back}}\right) - 2j\left(\frac{\Delta f_0}{f_0}\right)\right] \tag{3}$$

where Q_0 is the unloaded quality factor when the sample is inserted in the cavity, whereas Q_0^{back} is the unloaded quality factor of the bare cavity. The error on the surface resistance and

the surface reactance is of 15 %. In figure 3, $\Delta R_S(H_{r.f.})$ at different temperatures is shown. The surface resistance linearly changes increasing the microwave surface field $H_{r.f.}$ until a threshold field H^* is attained. H^* represents the field value above which non linear effects appear. For values larger than H^* the line shape of the resonance peak starts to deviate from a pure Lorentzian curve, therefore the R_S values cannot be correctly estimated. H^* is strongly temperature dependent and its value is significantly lower than the H^c_{C1} bulk values previously reported for this material.[16]

In conventional nonlinear materials, it is straightforward to see that third order products must increase with the third power of input main tones.[2, 3] In the case of MgB_2, IMD slopes range between 1.5 and 2.3, resembling granular YBCO thin film behavior.[4, 5, 6, 7, 8, 9] This unconventional behaviour might have different extrinsic origins: *a)* a hysteretic process dominated by the creation and the irreversible motion of Josephson vortices in grain boundaries;[17, 18] or *b)* heating effects due to the low thermal conductivity of the film substrate. The latter source of nonlinearity can be ruled out because of the high thermal conductivity of sapphire and since for each sample the IMDs remain unchanged when δf is varied between 10 to 50 kHz.[12] In support of hysteretic Josephson flux penetration there are several considerations. As recently reported,[19] granular MgB_2 is characterized by amorphous grain boundaries of metallic character with thickness ranging between 5 and 20 nm. Thus we can model the system by a network of S-N-S Josephson coupled grains. In addition, IMD slopes close to 2 and almost temperature independent can be induced by a linear dependence of the surface impedance on the applied microwave field.[7] Indeed this is the observed form of the nonlinear dependence of R_S in our films. In a simple granular model, the IMD amplitude decreases with the increasing temperature,[13] as we observe. And finally the dimensionless parameter $r = \Delta(1/Q)/(-2\Delta f/f_0)$ [17, 20] is of the order of unity for all samples (see table I). All these experimental observations point to a model of Josephson coupled grains where the main extrinsic mechanism for microwave losses is the generation and the motion of Johsepson vortices in grain boundaries. The metallic nature of these grain boundaries might explain the lack of distinctive evidence for weak link effects in dc magnetisation measurements,[21] where proximity effect makes the sample a well connected superconducting domain without strongly affecting the critical current density even in reduced critical temperature samples. Indeed the MgB_2 case may resemble that of $YBa_2Cu_3O_{7-\delta}$/silver composites,[22] where the enhanced intergranular current density was

interpreted as being due to improved coupling between grains by proximity effect in the intergranular silver.

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TABLE I: Main superconducting properties of the samples under test. The r factor is calculated at the reduced temperature t=T/T$_C$=0.57 for sample #1 and at t=0.5 for the remaining samples.

sample	**#1**	**#2**	**#3**
T_c [K]	21.2	24.2	31.4
ΔT_c [K]	0.6	2.1	8
$R_S(T = 12K)$ [mΩ]	13	8.9	6.1
$r = \Delta(1/Q)/(-2\Delta f/f_0)$	0.6	0.4	0.4

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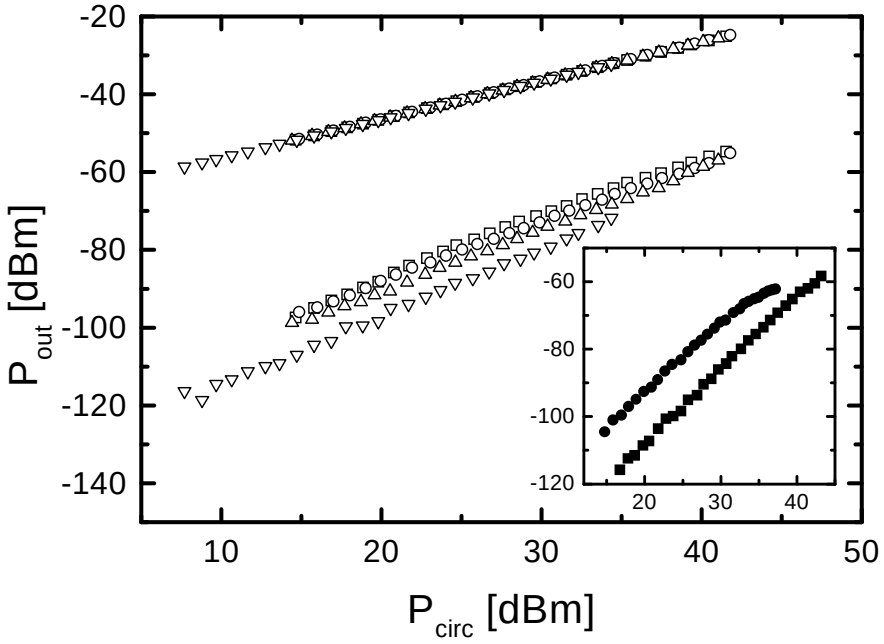


FIG. 1: The output power of the fundamental signal $P_{out,1}$ and of the IMD products $P_{out,3}$ displayed for sample #3 as a function of the circulating power at the reduced temperatures: $t=T/T_C=0.38$ (□), t=0.48 (○), t=0.57 (△) and t=0.72 (▽). In the inset we show P_{out} vs P_{circ} for the samples #1 and #2 at t=0.57 (■) and 0.62 (●) respectively for comparison.

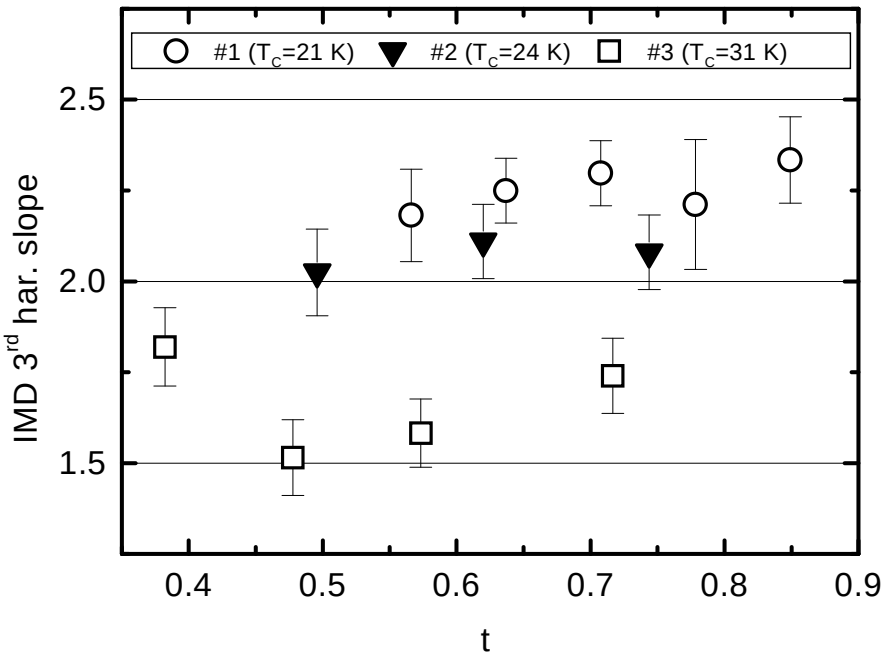


FIG. 2: The IMD slopes as a function of the reduced temperature t=T/T_C for all the samples under test: #1 (○), #2 (▼), #3 (□).

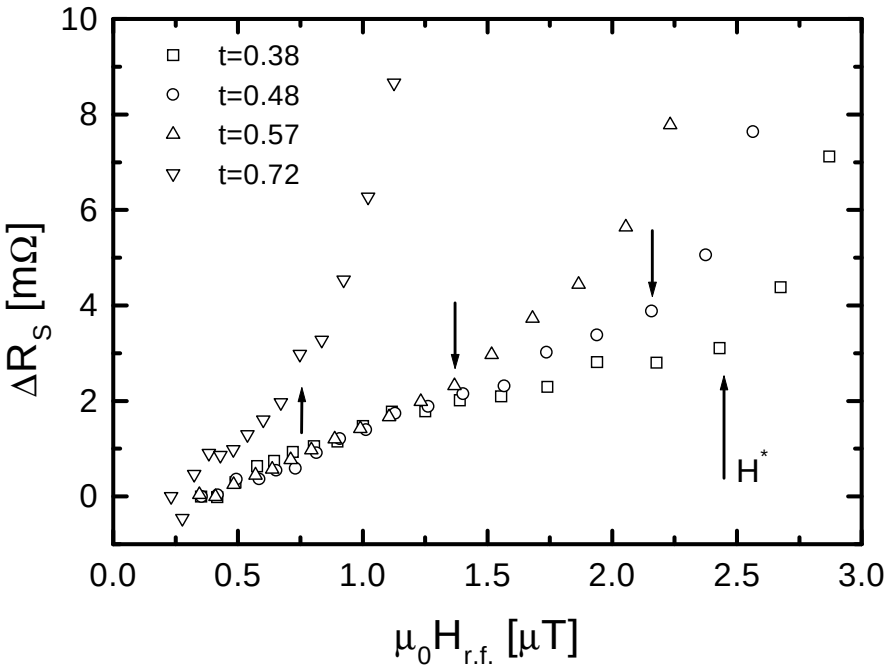


FIG. 3: Change in the surface resistance values as a function of the applied microwave field at the following reduced temperatures: t=0.38 (□), t=0.48 (○), t=0.57 (△) and t=0.72 (▽). The arrows indicate the threshold field H^* above which non linear effects starts to show up.